	Application No.	Applicant(s)		
Notice of Allowability	10/812,117	ELLIOTT ET AL.		
	Examiner	Art Unit		
	Ron E. Pompey	2812		
The MAILING DATE of this communication apper All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED or other appropriate comm GHTS. This application is	in this application. If not included nunication will be mailed in due cou	rse. THIS	
1. This communication is responsive to 6/22/07.				
2. The allowed claim(s) is/are <u>1,5-8 and 11-22</u> .				
3. Acknowledgment is made of a claim for foreign priority un	nder 35 U.S.C. § 119(a)-(d)	or (f).		
a) All b) Some* c) None of the:				
1. Certified copies of the priority documents have been received.				
2. Certified copies of the priority documents have been received in Application No				
3. Copies of the certified copies of the priority documents have been received in this national stage application from the				
International Bureau (PCT Rule 17.2(a)).				
* Certified copies not received:				
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.				
4. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.				
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.				
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached				
1) hereto or 2) to Paper No./Mail Date				
(b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date				
Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).				
6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.				
Attachment(s)	5 			
1. Notice of References Cited (PTO-892)	_	nformal Patent Application		
2. Notice of Draftperson's Patent Drawing Review (PTO-948)		 Interview Summary (PTO-413), Paper No./Mail Date 		
3. Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date	7. 🛛 Examiner'	7. ⊠ Examiner's Amendment/Comment		
4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. 🛛 Examiner'	s Statement of Reasons for Allowa	nce	
	9.	MICHAEL LEBENTRITT		
		PERVISORY PATERIT EXAMINE	ED	

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Krista Powell on June 22, 2007.

The application has been amended as follows:

In claim 1 line 5, after "substrate", delete – and --.

In claim 1 line 5, after "substrate", insert --

forming a silicide layer on said contact surface of said semiconductor substrate; forming a metal nitride layer upon a sidewall of said contact hole; and --.

In claim 1 line 9, after "physical contact", delete -- contact surface on the semiconductor substrate, wherein the single layer of metal comprises a material selected from the group consisting of AlAg, AlAu, AlMn, AlNa, AlW, AlCuZn, and AlNi. In claim 1 line 9, after "physical contact", insert -- said silicide layer and said metal nitride layer --.

After claim 21, add new claim -- 22. The method according to claim 1, wherein the single layer of metal comprises a material selected from the group consisting of AlAg, AlAu, AlMn, AlNa, AlW, AlCuZn, and AlNi --.

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Allowable Subject Matter

2. Claims 1, 5-8 and 11-22 are allowed.

3. The following is an examiner's statement of reasons for allowance: The primary reasons for the allowance of claims 1, 5-8 and 11-22 were stated in the office action mailed December 1, 2005.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ron E. Pompey whose telephone number is (571) 272-1680. The examiner can normally be reached on 9AM - 5PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael S. Lebentritt can be reached on (571) 272-1873. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

6/22/07

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